

TENTATIVE TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE (π -MOS V)

2SK2992

HIGH SPEED, HIGH CURRENT SWITCHING APPLICATIONS

CHOPPER REGULATOR, DC-DC CONVERTER AND MOTOR DRIVE APPLICATIONS

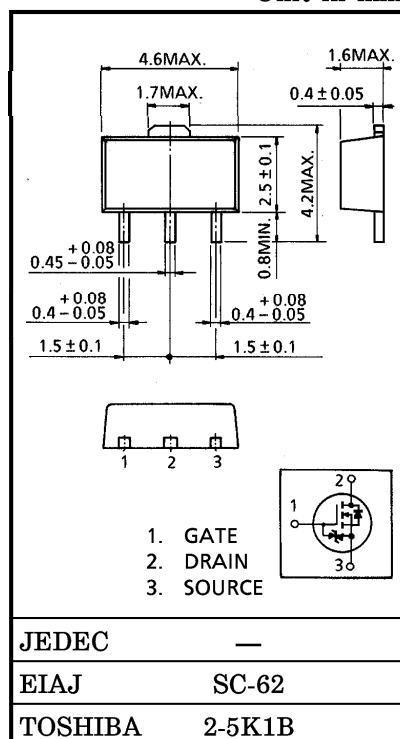
- Low Drain-Source ON Resistance : $R_{DS(ON)} = 2.2\Omega$ (Typ.)
- High Forward Transfer Admittance : $|Y_{fs}| = 0.9S$ (Typ.)
- Low Leakage Current : $I_{DSS} = 100\mu A$ (Max.) ($V_{DS} = 200V$)
- Enhancement-Mode : $V_{th} = 2.0 \sim 3.5V$ ($V_{DS} = 10V$, $I_D = 1mA$)

MAXIMUM RATINGS ($T_a = 25^\circ C$)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Drain-Source Voltage	V_{DSS}	200	V
Drain-Gate Voltage ($R_{GS} = 20k\Omega$)	V_{DGR}	200	V
Gate-Source Voltage	V_{GSS}	± 20	V
Drain Current	DC	I_D	1
	Pulse	I_{DP}	3
Drain Power Dissipation***	P_D	1.5	W
Single Pulse Avalanche Energy**	E_{AS}	36	mJ
Avalanche Current	I_{AR}	1	A
Repetitive Avalanche Energy*	E_{AR}	0.15	mJ
Channel Temperature	T_{ch}	150	$^\circ C$
Storage Temperature Range	T_{stg}	$-55 \sim 150$	$^\circ C$

INDUSTRIAL APPLICATIONS

Unit in mm



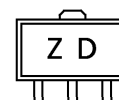
JEDEC

EIAJ SC-62

TOSHIBA 2-5K1B

Weight : 0.05g (Typ.)

MARKING



THERMAL CHARACTERISTICS

CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance, Channel to Ambient	$R_{th(ch-a)}$	250	$^\circ C/W$

Note ;

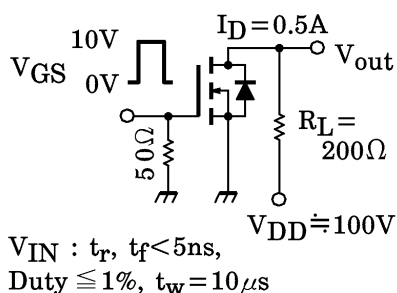
* Repetitive rating ; Pulse Width Limited by Max. junction temperature.

** $V_{DD} = 50V$, Starting $T_{ch} = 25^\circ C$, $L = 56.7mH$, $R_G = 25\Omega$, $I_{AR} = 1A$ *** Mounted on ceramic substrate ($1inch^2 \times 0.8t$)**This transistor is an electrostatic sensitive device.****Please handle with caution.**

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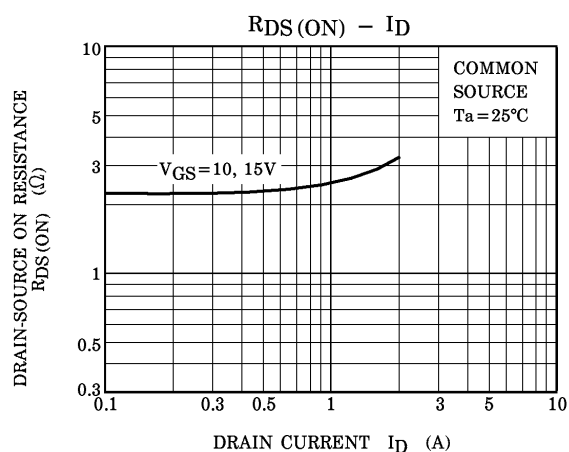
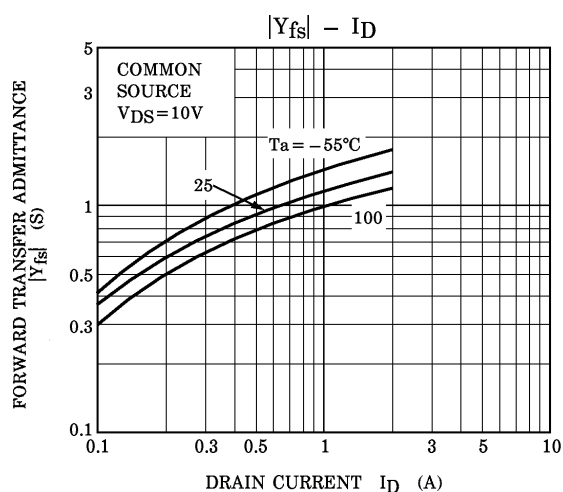
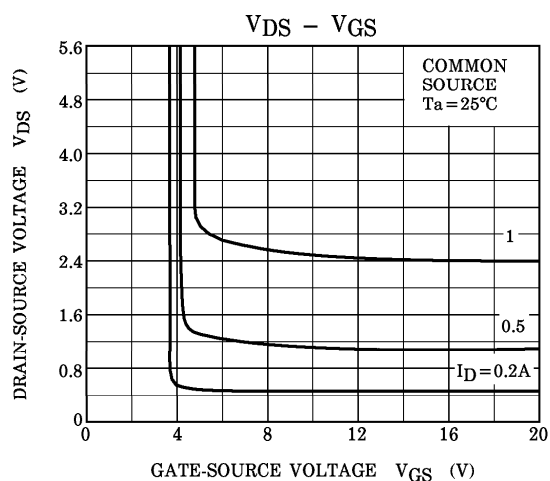
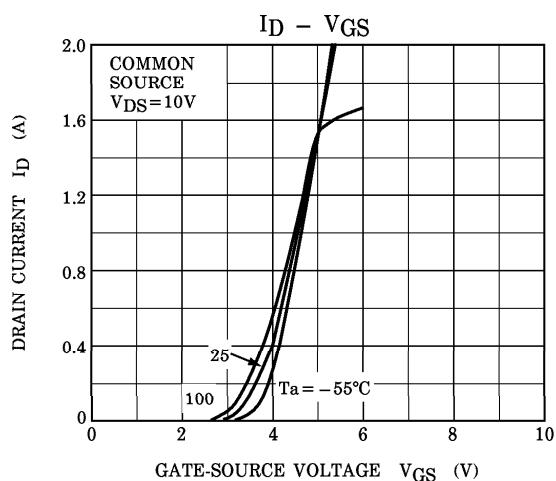
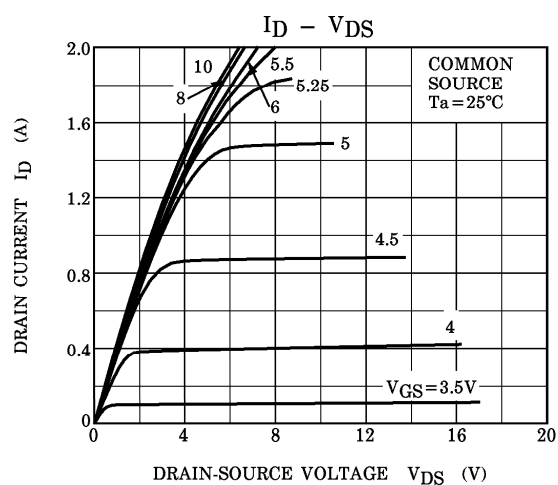
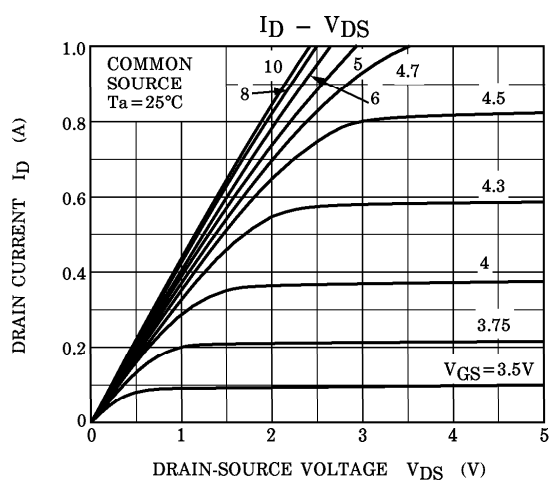
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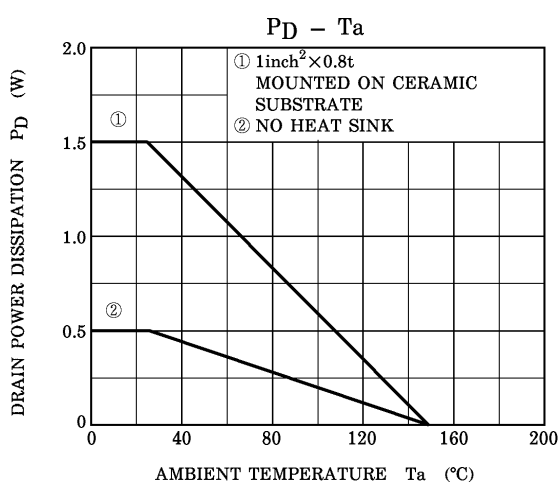
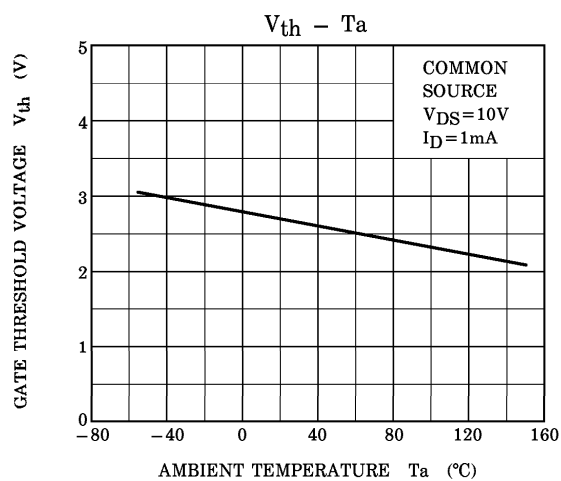
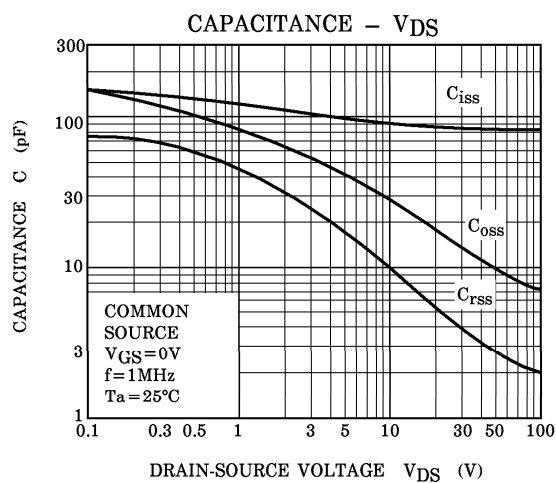
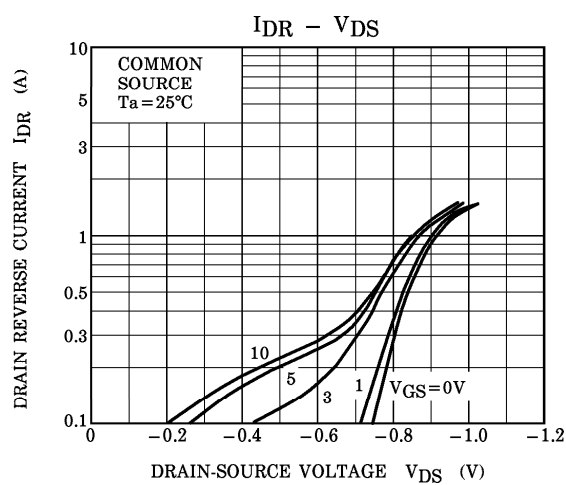
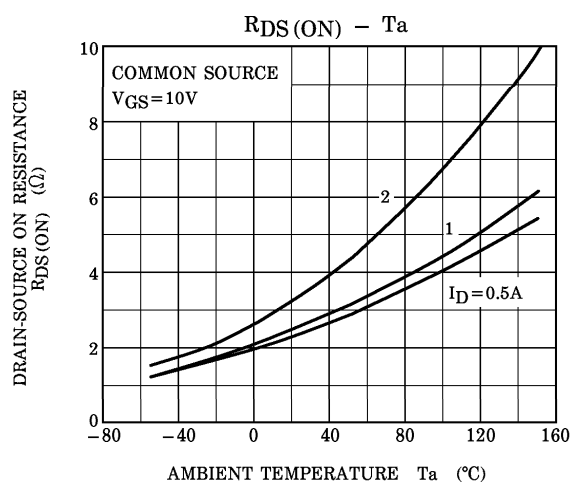
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

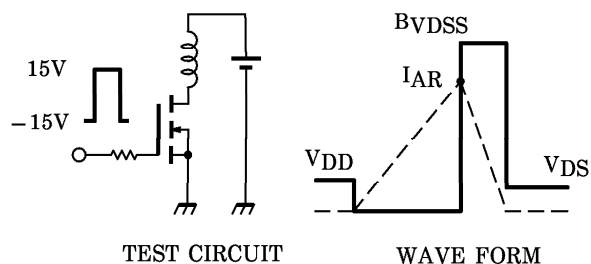
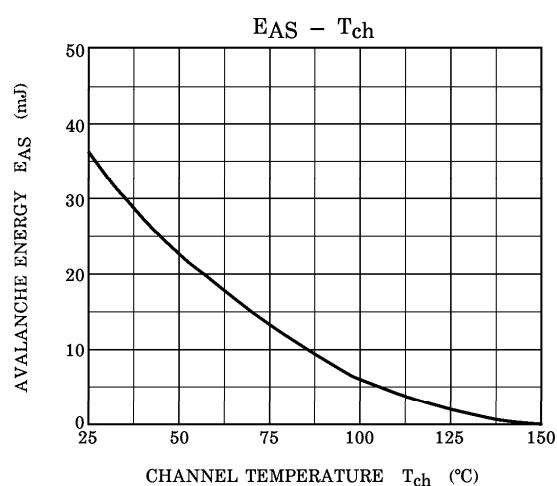
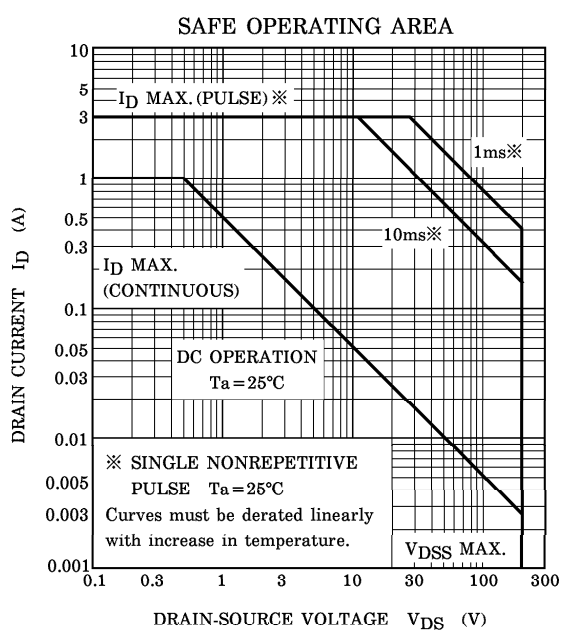
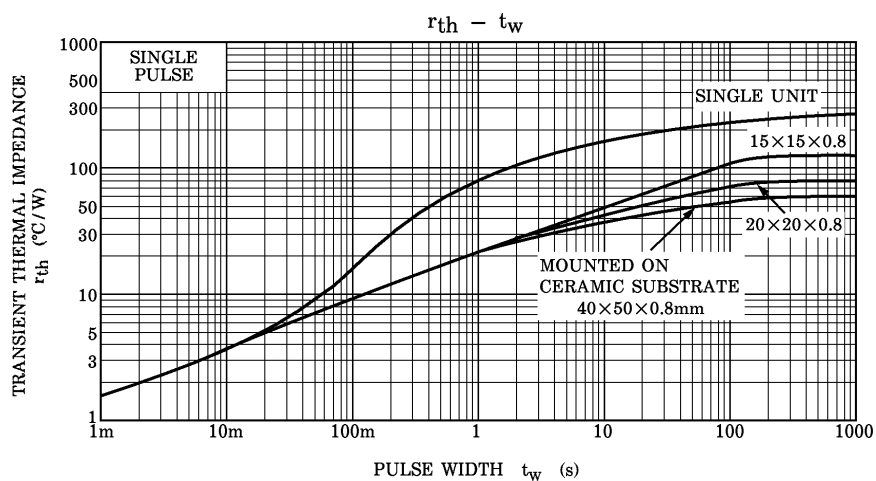
CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		I_{GSS}	$V_{GS} = \pm 16V, V_{DS} = 0V$	—	—	± 10	μA
Drain Cut-off Current		I_{DSS}	$V_{DS} = 200V, V_{GS} = 0V$	—	—	100	μA
Drain-Source Breakdown Voltage		$V_{(BR) DSS}$	$I_D = 10mA, V_{GS} = 0V$	200	—	—	V
Gate Threshold Voltage		V_{th}	$V_{DS} = 10V, I_D = 1mA$	2.0	—	3.5	V
Drain-Source ON Resistance		$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 0.5A$	—	2.2	3.5	Ω
Forward Transfer Admittance		$ Y_{fs} $	$V_{DS} = 10V, I_D = 0.5A$	0.5	0.9	—	S
Input Capacitance		C_{iss}	$V_{DS} = 10V, V_{GS} = 0V$ $f = 1MHz$	—	90	—	pF
Reverse Transfer Capacitance		C_{rss}		—	10	—	
Output Capacitance		C_{oss}		—	30	—	
Switching Time	Rise Time	t_r		—	9	—	ns
	Turn-on Time	t_{on}		—	17	—	
	Fall Time	t_f		—	16	—	
	Turn-off Time	t_{off}		—	45	—	
Total Gate Charge (Gate-Source Plus Gate-Drain)		Q_g	$V_{DD} \doteq 160V, V_{GS} = 10V$ $I_D = 1A$	—	3.0	—	nC
Gate-Source Charge		Q_{gs}		—	1.8	—	
Gate-Drain ("Miller") Charge		Q_{gd}		—	1.2	—	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Continuous Drain Reverse Current	I_{DR}	—	—	—	1	A
Pulse Drain Reverse Current	I_{DRP}	—	—	—	3	A
Diode Forward Voltage	V_{DSF}	$I_{DR} = 1A, V_{GS} = 0V$	—	—	—1.5	V
Reverse Recovery Time	t_{rr}	$I_{DR} = 1A, V_{GS} = 0V$	—	85	—	ns
Reverse Recovery Charge	Q_{rr}	$dI_{DR} / dt = 100A / \mu s$	—	190	—	nC







Peak $I_{AR} = 1\text{A}$, $R_G = 25\Omega$
 $V_{DD} = 50\text{V}$, $L = 56.7\text{mH}$

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - V_{DD}} \right)$$